

<b>Notice of References Cited</b>	Application/Control No. 10/748,308	Applicant(s)/Patent Under Reexamination WON ET AL.	
	Examiner Thinh T. Nguyen	Art Unit 2818	Page 1 of 1

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	C	US-6,576,053	06-2003	Kim et al.	117/89
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	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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